



## SHENZHEN SKIHOTAR SEMICONDUCTOR CO., LTD.

# FCC REPORT

Prepared For :	SHENZHEN SKIHOTAR SEMICONDUCTOR CO., LTD. A1806, Golden Central Business Building, No. 3037 Jintian Road, Futian District, Shenzhen, China
Product Name:	DDR4 MEMORY
Trade Name:	SKIHOTAR 技宏
Model :	DDR4 Memory Module, STxU3xxxxxx, STxL3xxxxxx, x stands for different frequency and capacity.
Prepared By :	Shenzhen BST Technology Co., Ltd. Building No.23-24, Zhiheng Industrial Park, Guankouer Road, Nantou, Nanshan District, Shenzhen, Guangdong, China
Test Date:	Dec. 25-26, 2018
Date of Report :	Dec. 27, 2018
Report No.:	BST181212043605ER



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## TEST REPORT DECLARATION

Applicant	:	SHENZHEN SKIHOTAR SEMICONDUCTOR CO., LTD.
Address	:	A1806, Golden Central Business Building, No. 3037 Jintian Road, Futian District, Shenzhen, China
EUT Description	:	DDR4 MEMORY
Model Number	:	DDR4 Memory Module, STxU4xxxxx, STxS4xxxxx, x stands for different frequency and capacity. <b>(Note: The series products have the same circuit diagram, PCB layout and functionality. the differences are the model name and appearance, so, we select DDR4 Memory Module to test.)</b>

Test Standards:

### FCC Part 15:2016

The EUT described above is tested by US to determine the maximum emission levels emanating from the EUT, the maximum emission levels are compared to the FCC Part 15 limits. The measurement results are contained in this test report. and Shenzhen BST Technology Co., Ltd. is assumed of full responsibility for the accuracy and completeness of these measurements. Also, this report shows that the EUT is to be technically compliant with the FCC requirements. This report applies to above tested sample only and shall not be reproduced in part without written approval of Shenzhen BST Technology Co., Ltd.

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*Mike Mo*  
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# 1. GENERAL INFORMATION

## 1.1. Report information

- 1.1.1. This report is not a certificate of quality; it only applies to the sample of the specific product/equipment given at the time of its testing. The results are not used to indicate or imply that they are application to the similar items. In addition, such results must not be used to indicate or imply that BST approves recommends or endorses the manufacture, supplier or use of such product/equipment, or that BST in any way guarantees the later performance of the product/equipment.
- 1.1.2. The sample/s mentioned in this report is/are supplied by Applicant, BST therefore assumes no responsibility for the accuracy of information on the brand name, model number, origin of manufacture or any information supplied.
- 1.1.3. Additional copies of the report are available to the Applicant at an additional fee. No third part can obtain a copy of this report through BST, unless the applicant has authorized BST in writing to do so.

## 1.2. Test Facility

The test site used to collect the data is located on the address of  
BSL Testing Co.,LTD.

(FCC Registered Test Site Number: 191509) on  
NO. 24, ZH Park, Nantou, Shenzhen, 518000 China

The Test Site is constructed and calibrated to meet the FCC requirements.

## 1.3. Test Uncertainty

(95% confidence levels,  $k=2$ )

Test Item	Uncertainty
Uncertainty for Radiation emission test (30MHz to 1GHz)	4.0dB



## 2. PRODUCT DESCRIPTION

### 2.1.EUT Description

Description	:	DDR4 MEMORY
Applicant	:	SHENZHEN SKIHOTAR SEMICONDUCTOR CO., LTD. A1806, Golden Central Business Building, No. 3037 Jintian Road, Futian District, Shenzhen, China
Manufacturer	:	SHENZHEN SKIHOTAR SEMICONDUCTOR CO., LTD. A1806, Golden Central Business Building, No. 3037 Jintian Road, Futian District, Shenzhen, China
Model Number	:	DDR4 Memory Module, STxU4xxxxx, STxS4xxxxx, x stands for different frequency and capacity.

### 2.2.Test Conditions

Temperature: 23~25 °C

Relative Humidity: 55~63 %



### 3. TEST RESULTS SUMMARY

**Table 1 Test Results Summary**

Test Items	Test Results
Conducted disturbance	N.A
Radiated disturbance	Pass

Remark: "N/A" means "Not applicable."



## 4. TEST EQUIPMENT USED

### 4.1. For Conducted Emission Test

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Test Receiver	Rohde & Schwarz	ESHS30	828985/018	Jun. 01, 18	1 Year
2.	Pulse Limiter	Rohde & Schwarz	ESH3-Z2	100006	Jun. 01, 18	1 Year
3.	L.I.S.N.	Rohde & Schwarz	ESH2-Z5	834549/005	Jun. 01, 18	1 Year
4.	Conical	Emtek	N/A	N/A	N/A	N/A
5.	Voltage Probe	Schwarzbeck	TK9416	N/A	Jun. 01, 18	1 Year
6.	Coaxial Switch	Anritsu	MP59B	6100214550	Jun. 01, 18	1 Year

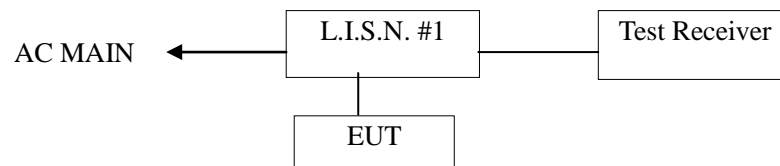
### 4.2. For Radiated Emission Measurement

Item	Equipment	Manufacturer	Model No.	Serial No.	Last Cal.	Cal. Interval
1.	Spectrum Analyzer	ANRITSU	MS2661C	6200140915	Jun. 01, 18	1 Year
2.	Test Receiver	Rohde&Schwarz	ESC830	828982/018	Jun. 01, 18	1 Year
3.	Bilog Antenna	Schwarzbeck	VULB9163	142	Jun. 01, 18	1 Year
4.	50 Coaxial Switch	Anritsu Corp	MP59B	6100237248	Jun. 01, 18	1 Year
5.	Cable	Schwarzbeck	AK9513	ACRX1	Jun. 01, 18	1 Year
6.	Cable	Rosenberger	N/A	FR2RX2	Jun. 01, 18	1 Year
7.	Cable	Schwarzbeck	AK9513	CRRX2	Jun. 01, 18	1 Year
8.	Cable	Schwarzbeck	AK9513	CRRX2	Jun. 01, 18	1 Year
9.	Single Phase Power Line Filter	MPE	23332C	N/A	Jun. 01, 18	1 Year
10.	Single Phase Power Line Filter	MPE	23333C	N/A	Jun. 01, 18	1 Year
11.	Signal Generator	HP	864A	3625U00573	Jun. 01, 18	1 Year



## 5. CONDUCTED EMISSION TEST

### 5.1. Block Diagram of Test Setup



(EUT: DDR4 MEMORY )

### 5.2. Test Standard

FCC Part 15: 2016

### 5.3. Conducted Emission Limit(Class B)

Frequency MHz	Limits dB( $\mu$ V)	
	Quasi-peak Level	Average Level
0.15 ~ 0.50	66 ~ 56*	56 ~ 46*
0.50 ~ 5.00	56	46
5.00 ~ 30.00	60	50

Notes: 1. \*Decreasing linearly with logarithm of frequency.

### 5.4. EUT Configuration on Test

The following equipments are installed on conducted emission test to meet Part 15 requirement and operating in a manner, which tends to maximize its emission characteristics in a normal application.

#### 5.4.1. EUT Information

Model Number : DDR4 Memory Module  
Serial Number : N/A

### 5.5. Operating Condition of EUT

5.5.1. Setup the EUT and simulators as shown in Section 5.1.

5.5.2. Turn on the power of all equipments.

5.5.3. Let the EUT work in test modes (On) and test it.





## 5.6. Test Procedure

The EUT is put on a table of non-conducting material that is 80cm high. The vertical conducting wall of shielding is located 40cm to the rear of the EUT. The power line of the EUT is connected to the AC mains through a Artificial Mains Network (A.M.N.). A EMI test receiver is used to test the emissions form both sides of AC line. The bandwidth of EMI test receiver is set at 9kHz.

The bandwidth of the test receiver is set at 9kHz.

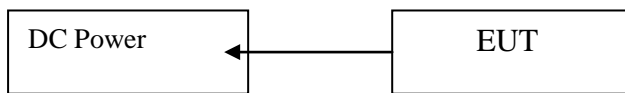
## 5.7. Test Result

**N.A**

## 6. RADIATED EMISSION MEASUREMENT

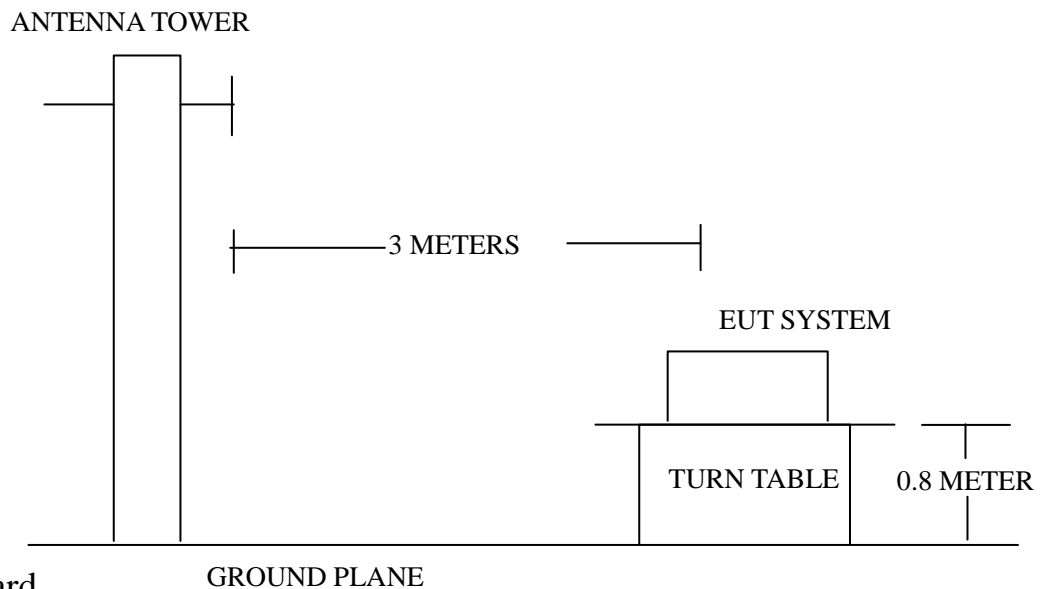
### 6.1. Block Diagram of EUT Configuration

#### 6.1.1. Block Diagram of connection between the EUT and the simulators



(EUT: DDR4 MEMORY)

#### 6.1.2. Semi-Anechoic Chamber Test Setup Diagram



### 6.2. Test Standard

FCC Part 15: 2016

### 6.3. Radiated Emission Limit(Class B)

FREQUENCY (MHz)	DISTANCE (Meters)	FIELD STRENGTHS LIMITS (dB $\mu$ V/m)
30 ~ 88	3	40.0
88 ~ 216	3	43.5
216 ~ 960	3	46.0
960 ~ 1000	3	54.0

Note:(1) The smaller limit shall apply at the edge between two frequency bands.

(2) Distance refers to the distance in meters between the measuring instrument antenna and the closed point of any part of the EUT or system.



## 6.4.EUT Configuration on Test

The following equipment are installed on Radiated Emission Measurement to meet the Commission requirements and operating regulations in a manner which tends to maximize its emission characteristics in normal application.

## 6.5.Operating Condition of EUT

- 6.5.1.Setup the EUT as shown on Section 6.1.2
- 6.5.2.Turn on the power of all equipments.
- 6.5.3.Let the EUT work in test mode(On) and measure it.

## 6.6.Test Procedure

The EUT is placed on a turn table which is 0.8 meter above ground. The turn table can rotate 360 degrees to determine the position of the maximum emission level. The EUT is set 3 meters away from the receiving antenna which is mounted on a antenna tower. The antenna can move up and down between 1 to 4 meters to find out the maximum emission level. Broadband antenna (calibrated by dipole antenna) are used as a receiving antenna. Both horizontal and vertical polarization of the antenna are set on measurement.

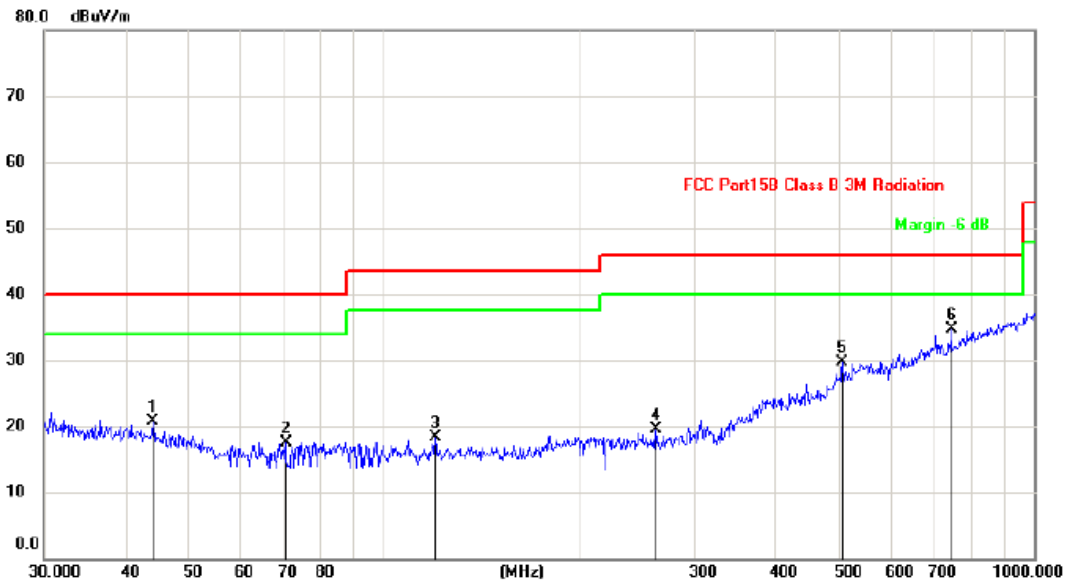
The bandwidth setting on the test receiver is 120 KHz.  
The EUT is tested in Semi-Anechoic Chamber. The frequency range from 30MHz to 1000 MHz is checked.All the test results are listed in Section 6.7. and all the scanning waveform are attached within **Appendix I**.

## 6.7.Test Result

**PASS**



# APPENDIX I Test Curves

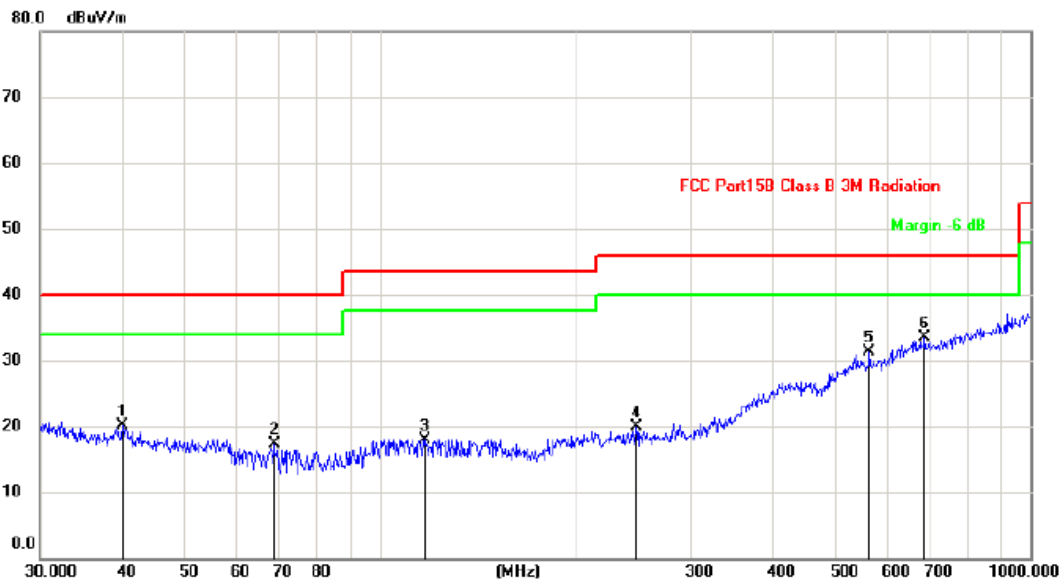


Site Chamber #1  
 Limit: FCC Part15B Class B 3M Radiation  
 EUT:  
 M/N:  
 Mode:  
 Note:

Polarization: *Horizontal*  
 Power: .  
 Distance: 3m

Temperature: 26  
 Humidity: 65 %

No.	Mk.	Freq.	Reading Level	Correct Factor	Measurement	Limit	Over	Antenna Height	Table Degree
		MHz	dBuV	dBuV/m	dBuV/m	dBuV/m	dB	cm	degree
1		44.1200	16.61	4.02	20.63	40.00	-19.37	QP	
2		70.5836	15.46	2.11	17.57	40.00	-22.43	QP	
3		119.8555	16.71	1.67	18.38	43.50	-25.12	QP	
4		261.9753	15.62	3.80	19.42	46.00	-26.58	QP	
5		506.4791	15.77	13.84	29.61	46.00	-16.39	QP	
6	*	744.8659	17.48	17.27	34.75	46.00	-11.25	QP	



Site Chamber #1 Polarization: *Vertical* Temperature: 26  
 Limit: FCC Part15B Class B 3M Radiation Power: . Humidity: 65 %  
 EUT: Distance: 3m  
 M/N:  
 Mode:  
 Note:

No.	Mk.	Freq.	Reading Level	Correct Factor	Measurement	Limit	Over	Antenna Height	Table Degree	
		MHz	dBuV	dBuV/m	dBuV/m	dBuV/m	dB	cm	degree	Comment
1		40.1347	15.36	4.72	20.08	40.00	-19.92	QP		
2		68.6310	15.15	2.19	17.34	40.00	-22.66	QP		
3		117.3602	16.40	1.55	17.95	43.50	-25.55	QP		
4		247.6819	17.27	2.68	19.95	46.00	-26.05	QP		
5		564.6389	16.80	14.48	31.28	46.00	-14.72	QP		
6	*	687.1507	16.28	17.24	33.52	46.00	-12.48	QP		



## **APPENDIX II**

### **(Photos of the EUT)**

**Photo 1 General Appearance of the EUT**



**Photo 2 General Appearance of the EUT**





**Photo 3 General Appearance of the EUT**



**Photo 4 Test scene**

